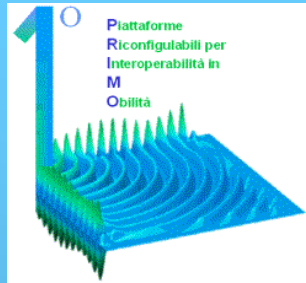


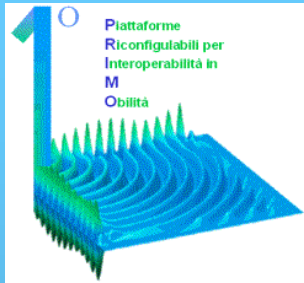
A Statistical Model for Estimating the Effect of Process Variations on Crosstalk Noise

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CERCOM-Dip. Elettronica
Politecnico di Torino



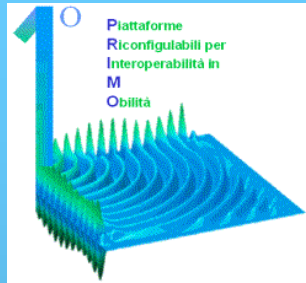
Agenda

- ✓ Introduction
- ✓ Proposed Method
- ✓ Experimental Results
- ✓ Conclusions



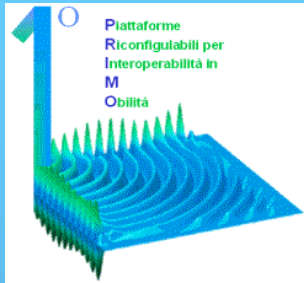
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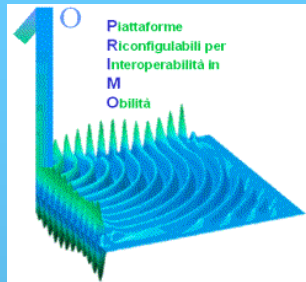
Introduction

- The interconnects analysis in modern deep sub-micron technologies can not be faced with traditional analysis methodologies.
- Statistical analysis seems to be a good solution to obtain early prediction about interconnects non-ideal phenomena (e.g. cross-talk, delay, ...).



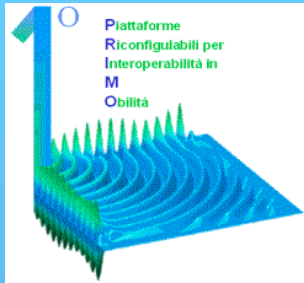
Introduction

- To obtain a good prediction:
 - a good electrical model is required, combining accuracy and computational efficiency.
 - parasitic parameters must be available from 2D/3D extraction.
 - switching activities and time windows are required for all aggressor lines.



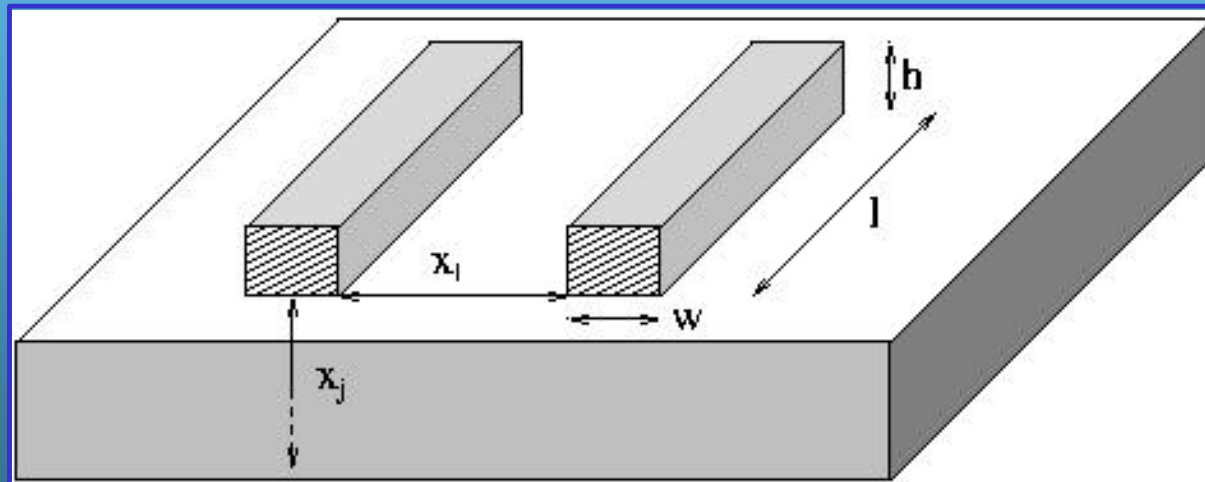
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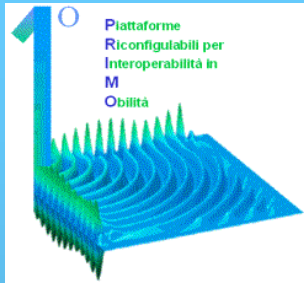


Case of study

- We concentrate on the case of coupled lines laying at the same metal level

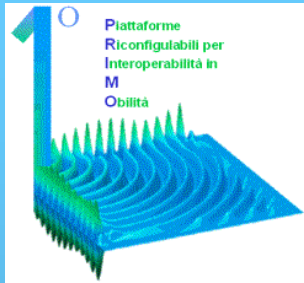


- Current work is dealing with process variations and their impact on cross-talk noise.



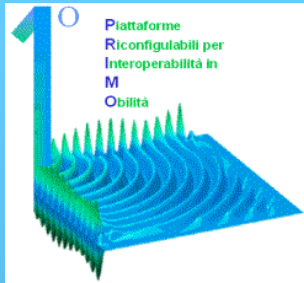
Problem formulation - I

- Considering the cross-talk noise voltage as a function $V_x(t) = g(t, p_1, p_2, \dots, p_n)$ of n statistically independent parameters (p_i).
- Supposing each parameter exhibits a normal distribution $p_i \sim N(\mu_{p_i}, \sigma_{p_i})$ (e.g. $C_c \sim N(\mu_{C_c}, \sigma_{C_c})$).
- We can consider any time value t for this analysis, since we concentrate on synchronous systems we pose $t = t_s$.



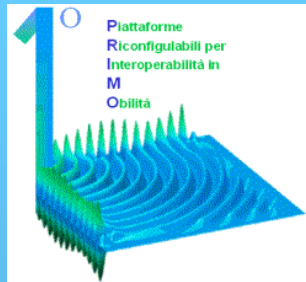
Problem formulation - II

- Starting from the statistical distribution of interconnects electrical parameters (R , C , C_c), we would like to obtain a closed form approximation of the statistical distribution of the cross-talk voltage.
- Two approaches can be pursued:
 - Approximating the voltage curve with an exponential function.
 - Representing the voltage expression as a partial second order Taylor expansion.



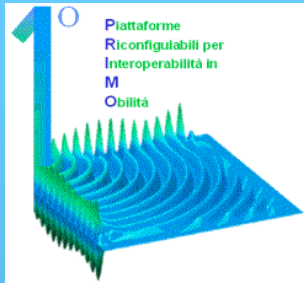
Requirements

- This method needs:
 - To know the statistical distribution of interconnects electrical parameters.
 - The electrical parameters to be statistically independent.
 - A closed form expression of the cross-talk voltage on the victim line.



CAVEAT

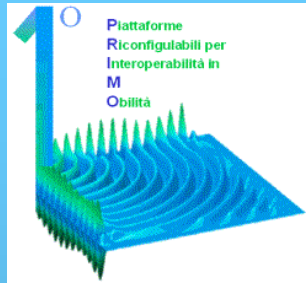
- A first order Taylor expansion would lead to the sum of Gaussian variables.
- Mixed second order Taylor expansion terms are not considered ($\partial^2 V / \partial p_i \partial p_j$) \rightarrow it is not treatable as a closed form.
- Electrical parameters independence: actually it is not true, however it is a simple case and a starting point to validate the methodology.



Proposed Method

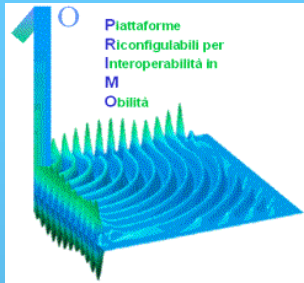
- Let's introduce a new set of random variables $\mathbf{x}_i = p_i - E[p_i]$
- Associating a random variable $\mathbf{h} = V_x(t_s)$ to the cross-talk voltage and taking a partial second order Taylor expansion we obtain:

$$\mathbf{h} \approx \mathbf{h}_0 + \sum_{i=1}^{i=n} \mathbf{S} a_i \mathbf{x}_i + \sum_{i=1}^{i=n} \mathbf{S} b_i \mathbf{x}_i^2$$



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Experimental results - I

Tech: 0.18 μm

$R_{\text{driver}} = 470 \Omega$

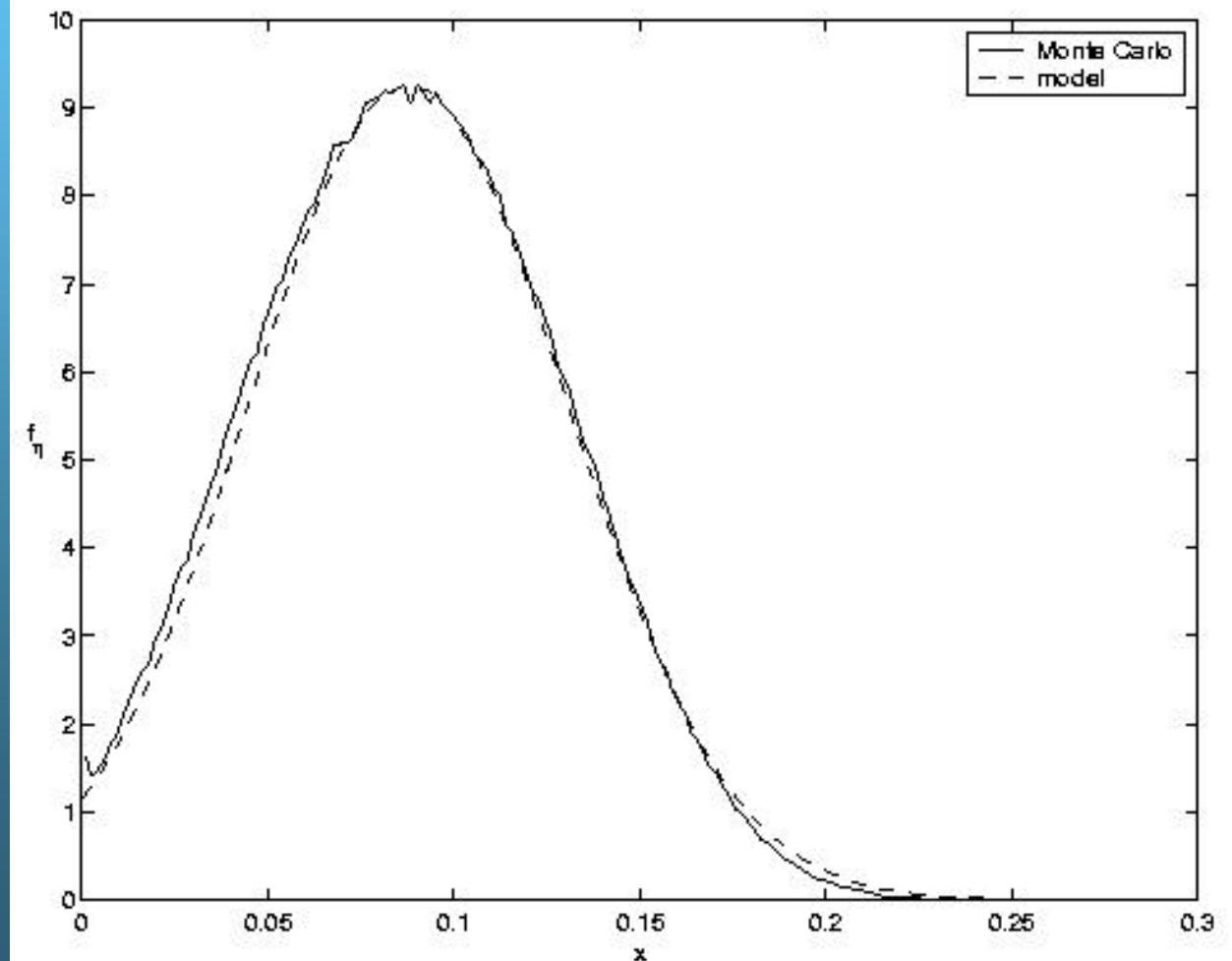
Line = 3 mm

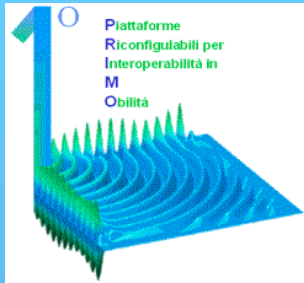
Rising time = 10 ps

Sampling period = 1 ns

C_c variation = 30%

C_a, C_v variation = 20%





Experimental results - II

Tech: 0.18 μm

$R_{\text{driver}} = 470 \Omega$

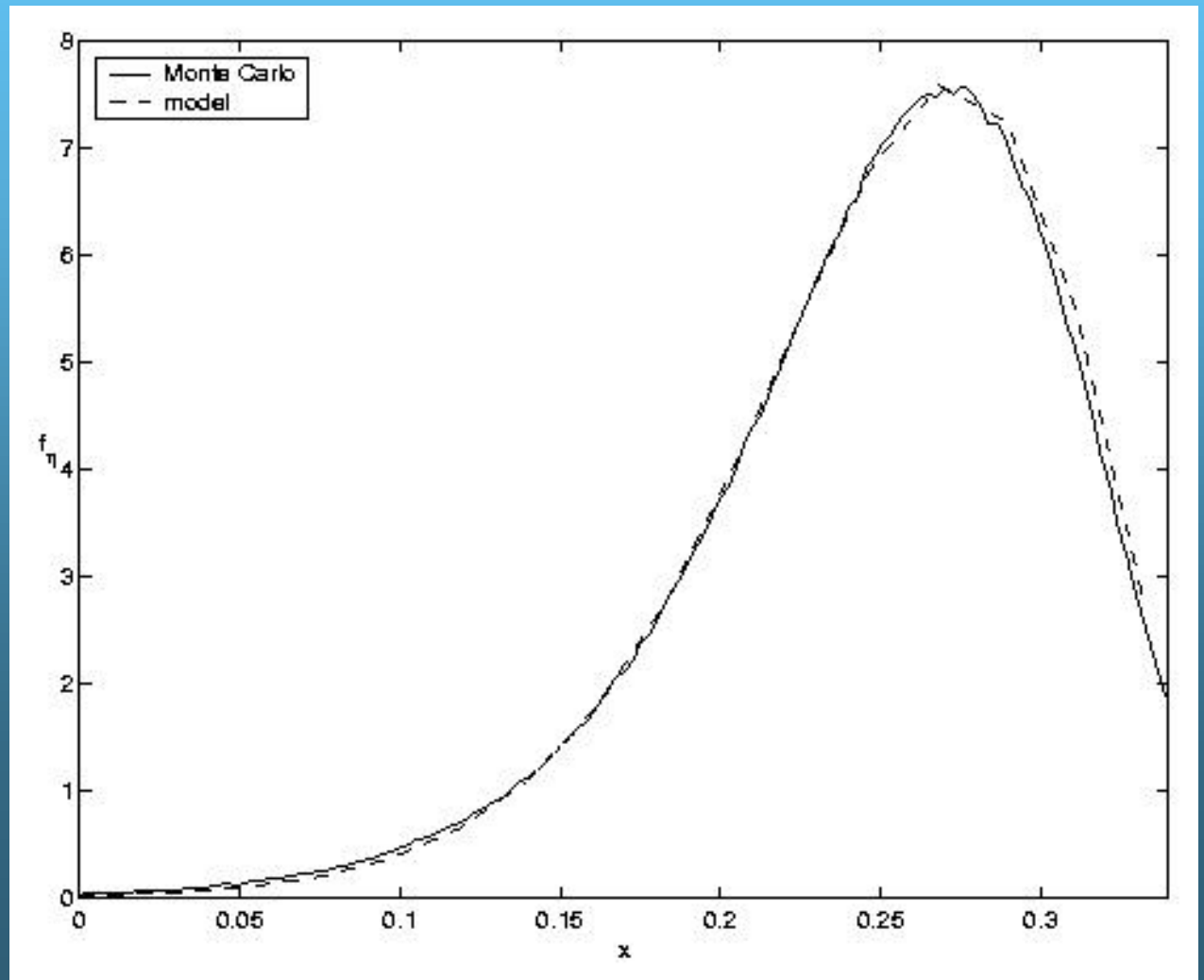
Line = 5 mm

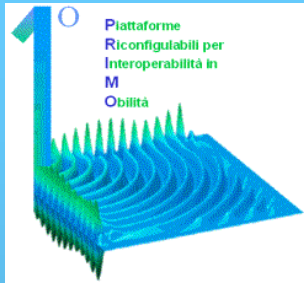
Rising time = 10 ps

Sampling period = 1 ns

C_c variation = 30%

C_a, C_v variation = 20%





Experimental results - III

Tech: $0.18 \mu\text{m}$

$R_{\text{driver}} = 470 \Omega$

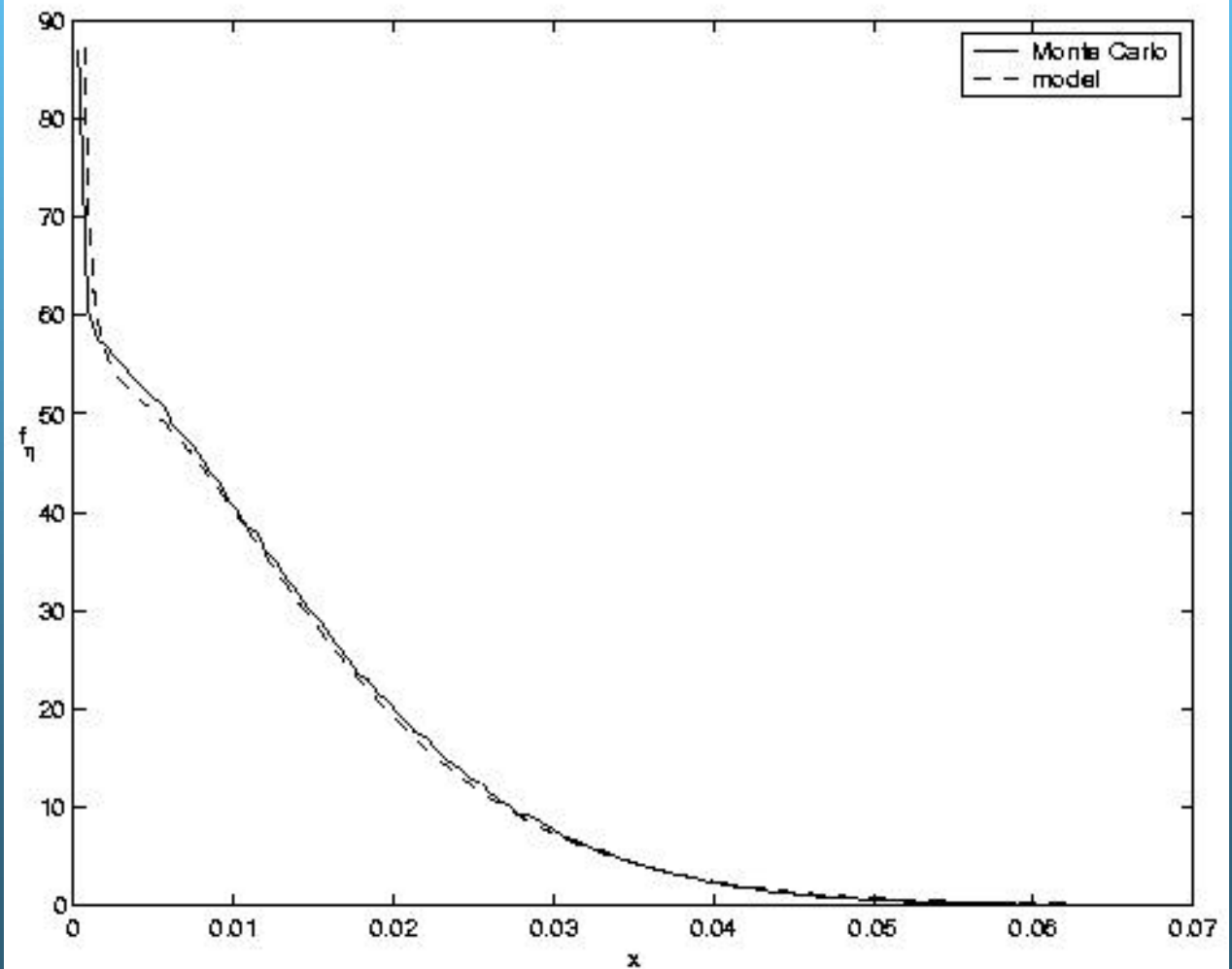
Line = 5 mm

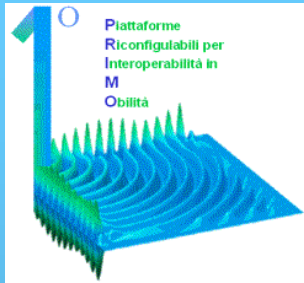
Rising time = 10 ps

Sampling period = 5 ns

C_c variation = 30%

C_a, C_v variation = 20%





Experimental results - III

Tech: 0.13 μm

$R_{\text{driver}} = 470 \Omega$

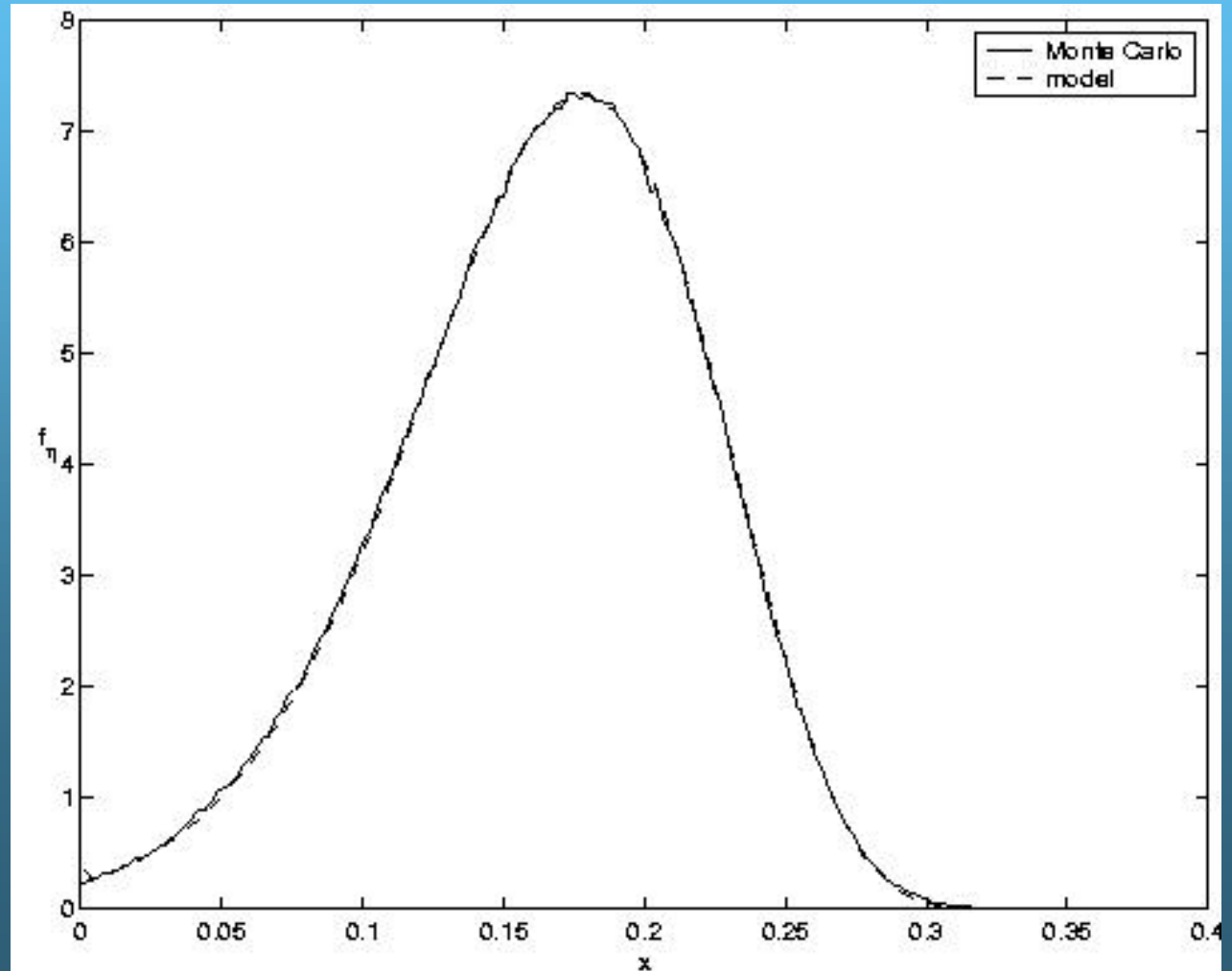
Line = 3 mm

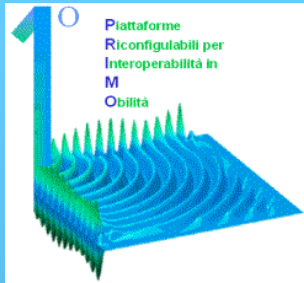
Rising time = 10 ps

Sampling period = 1 ns

C_c variation = 30%

C_a, C_v variation = 20%





Experimental results - IV

Tech: $0.13 \mu\text{m}$

$R_{\text{driver}} = 470 \Omega$

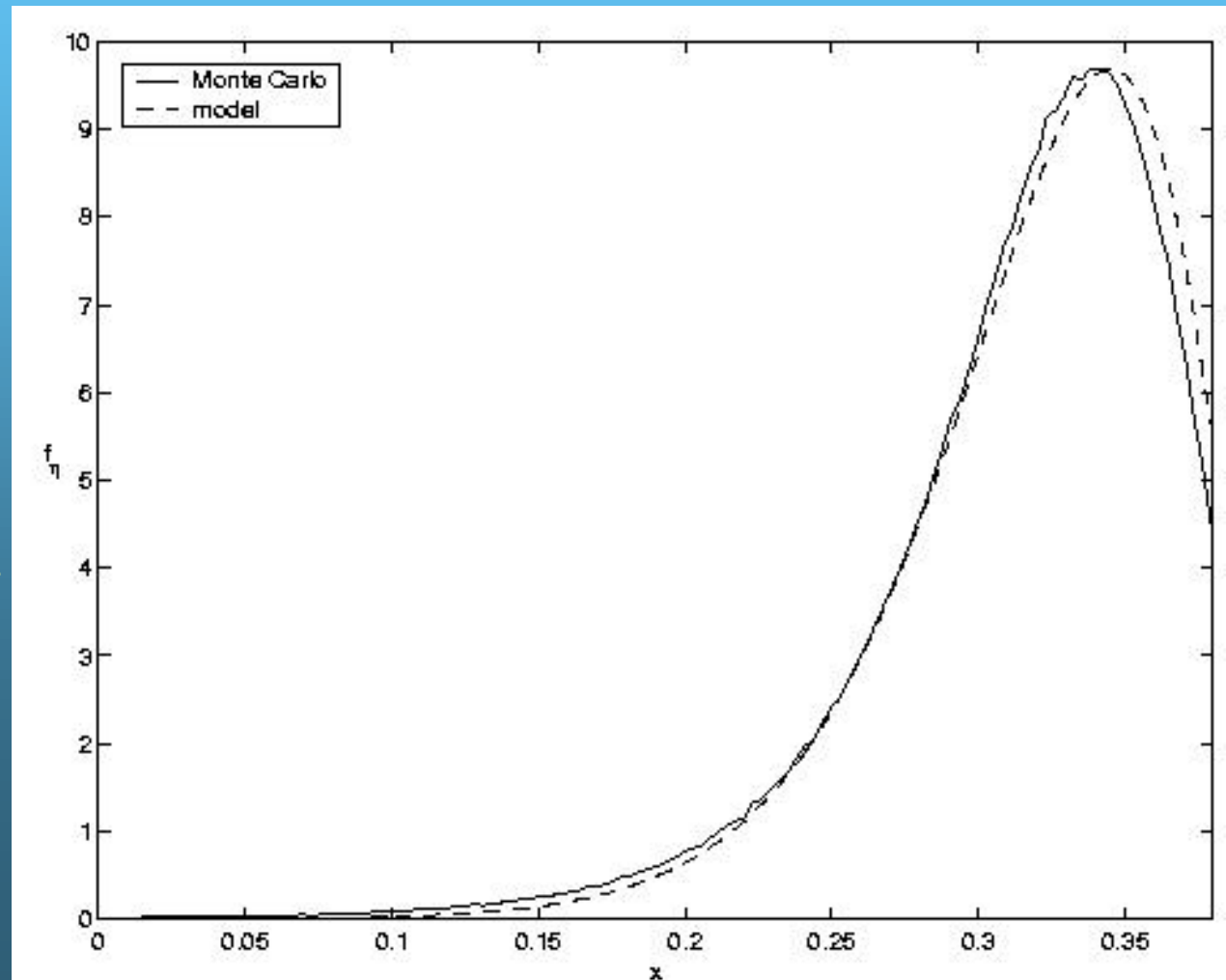
Line = 5 mm

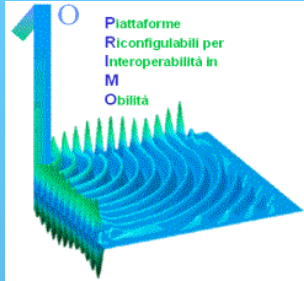
Rising time = 10 ps

Sampling period = 1 ns

C_c variation = 30%

C_a, C_v variation = 20%





Experimental results - V

Tech: $0.13 \mu\text{m}$

$R_{\text{driver}} = 470 \Omega$

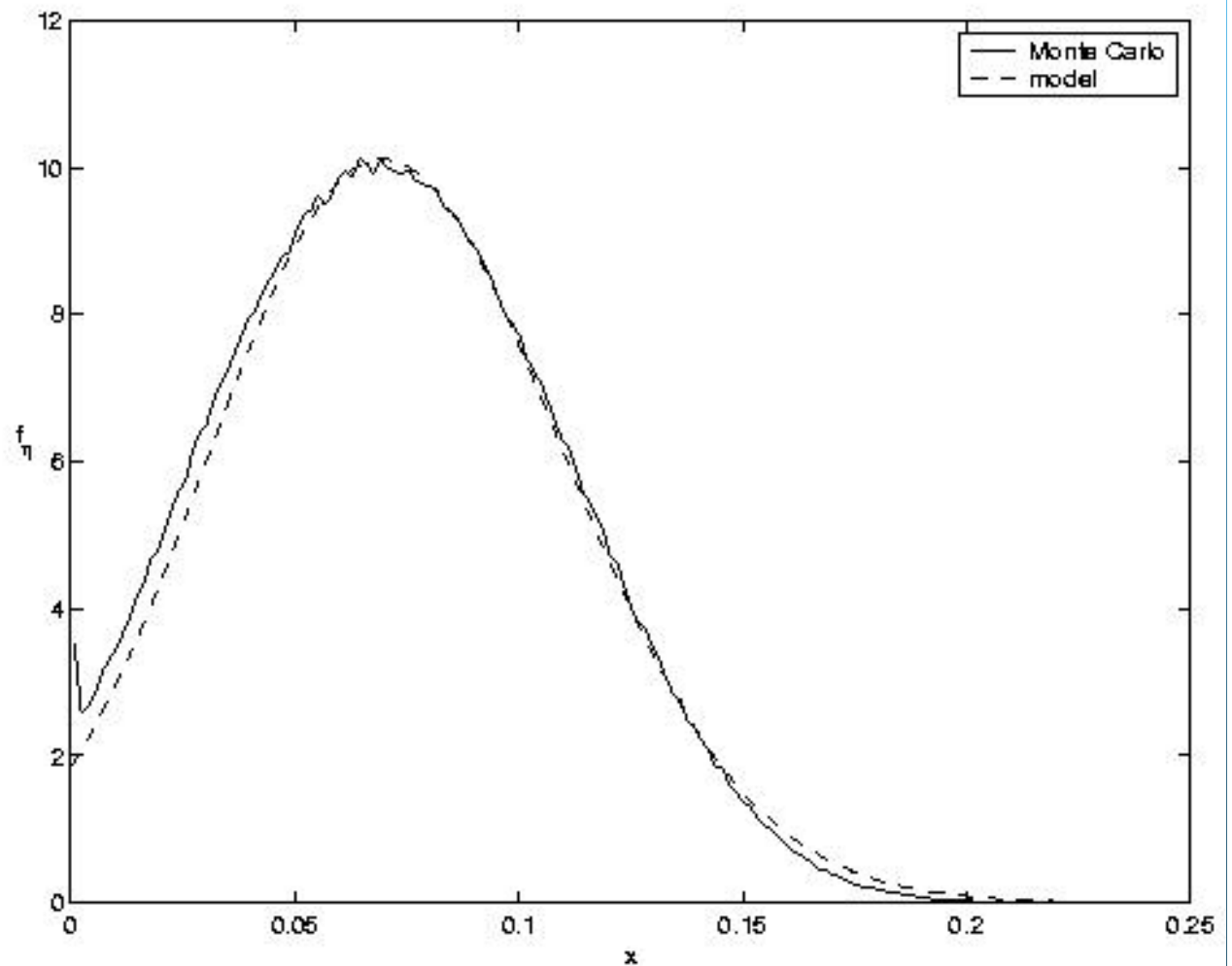
Line = 5 mm

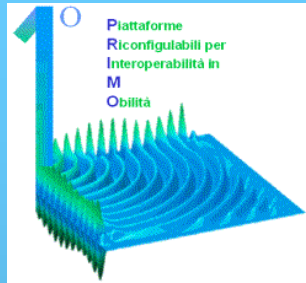
Rising time = 10 ps

Sampling period = 5 ns

C_c variation = 30%

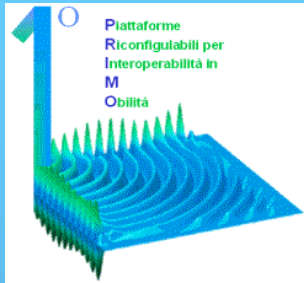
C_a, C_v variation = 20%





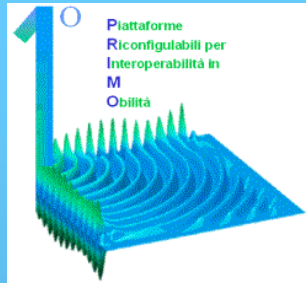
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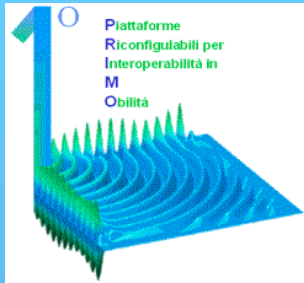
Conclusions - I

- A statistical model for the evaluation of the cross-talk depending on process variations has been proposed
- Even if some assumptions are rather rough, preliminary results are interesting



Conclusions - II

- The following actions are planned
 - Taking into account parameters correlation
 - Trying the proposed model on more complex structures
 - Developing models based on pure numerical-simulative approach
 - Concentrate on the cross-talk delay phenomenon



Contact Author

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Ph.D.

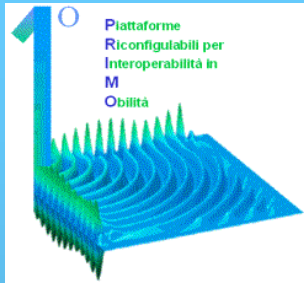
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Web: www.vlsilab.polito.it

Reconfigurable Platforms for
Mobile Interoperability – FIRB



Proposed Method - II

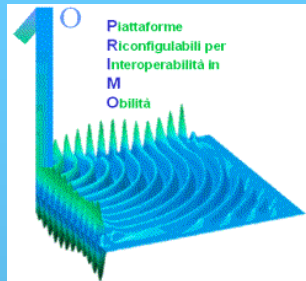
- For 2 lines we obtain:

$$\mathbf{h} \gg \mathbf{h}_0 + a_1 \mathbf{x}_1 + a_2 \mathbf{x}_2 + b_1 \mathbf{x}_1^2 + b_2 \mathbf{x}_2^2$$

- Since $\mathbf{h} = V_x(t_s)$, the cross-talk voltage statistical distribution can be evaluated from:

$$F_h(z) = P(\mathbf{h} \leq z)$$

$$= P(\mathbf{h}_0 + a_1 \mathbf{x}_1 + a_2 \mathbf{x}_2 + b_1 \mathbf{x}_1^2 + b_2 \mathbf{x}_2^2 \leq z)$$



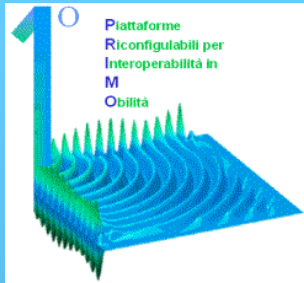
Proposed Method - III

- We can introduce

$$z_i = a_i x_i + b_i x_i^2$$

- η statistical distribution can be obtained from ζ_i distribution:

$$P(\mathbf{h} \ \& \ \mathbf{z}) = P(\mathbf{h}_0 + \mathbf{z}_1 + \mathbf{z}_2 \ \& \ \mathbf{z})$$



Proposed Method - IV

- So

- If $b > 0$

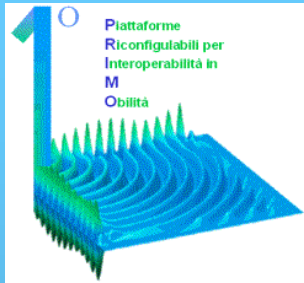
$$P(z \text{ \& } z) = P(ax+bx^2 \text{ \& } z) = P(z_1 \text{ \& } x \text{ \& } z_2)$$

- If $b < 0$

$$P(z \text{ \& } z) = P(ax+bx^2 \text{ \& } z) = P(x \text{ \& } z_2) + P(x^3 \text{ \& } z_1)$$

- Where z_1 and z_2 are the roots of

$$bx^2+ax-z = 0$$



Proposed Method - V

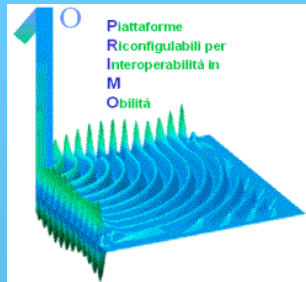
- Since p_i where assumed to be gaussian and independent $\mathbf{x}_i = p_i - E[p_i]$ are gaussian and independent with $\mu_i = 0$

– If $b > 0$

$$F_z(z) = P(\mathbf{z} \leq z) = F_x(z_2) - F_x(z_1)$$

– If $b < 0$

$$F_z(z) = P(\mathbf{z} \leq z) = F_x(z_2) + 1 - F_x(z_1)$$



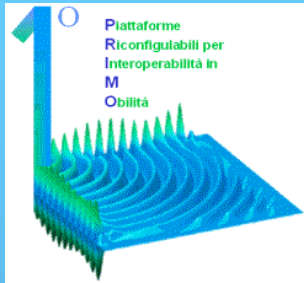
Proposed Method - VI

- To obtain the probability density function (pdf) of η we can calculate ζ pdf.

$$f_z(z) = dF_z(z)/dz$$

$$f_z(z) = 1/\Delta [f_x(z_2) - f_x(z_1)]$$

- Where $\Delta = \sqrt{(a^2 + 4bz)}$



Proposed Method - VII

- Thus if $\theta = \zeta_1 + \zeta_2$

$$f_q(z) = f_{z_1}(z) * f_{z_2}(z)$$

- So since $\eta = \eta_0 + \theta$

$$f_h(y) = f_q(z - \mathbf{h}_0)$$